

To Our Valued Distributors,

[NOTICE] Terminal Plating Change

First of all, we would like to take this opportunity to thank you for the excellent business relationship between the two companies and we look forward to a successful continuous partnership in the future.

1. Change Item : Terminal plating (Sn-Bi to Pure-Sn)

Please refer to attached Appendix for detail of the change and evaluation result.

2. Reason and Background

In order to unify specifications of plating and to promote "Pure-Sn" plating of terminal

As you know, demand for environmentally friendly semiconductor products has risen day by day. Number of customers who demand "Bismuth -free terminal plating" is also increasing. We have individually corresponded about the demand. By the individual correspondences, number of specification of the Pure-Sn plating has increased and the specifications made working efficiency worse. We like to unify specifications of terminal plating, promoting "Pure Sn" plating.

3. Applicable Products : Please see next page

4. Schedule : Sep, 1, 2015 ~

We will start shipment of pure Sn plated product in Sep 2015.

Actual timing of each product will be fixed, depending on order volume & inventory status.

If you have any questions, please let us know by Mar.31 2015. I appreciate your understanding and cooperation

Sincerely yours,

1. Sakashita

Tom Sakashita General Manager, Device Sales & Marketing Dep. Micro Devices Operations Division

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Applicable Products

C17F57F401100 QFF C17M01F00C100 TQF C17Y05F00C100 TQF D13503F01A200 QFF D13504F00A200 QFF D13506F00A200 QFF D13513F01A100 QFF D13513F00A100 QFF D13513F00A100 QFF D13513F00A100 QFF D13513F00A100 QFF D13513F00A100 QFF D13700F01A100 QFF D13700F02A100 TQF D13700F02A100 QFF	P13-64Pins P15-128Pins P13-64Pins		
C17M01F00C100 TQF C17Y05F00C100 TQF D13503F01A200 QFF D13504F00A200 QFF D13505F00A200 QFF D13506F00A200 QFF D13513F01A100 QFF D13513F00A100 QFF D13517F00A100 QFF D13700F01A100 TQF D13700F02A100 TQF			
C17Y05F00C100 TQF D13503F01A200 QFF D13504F00A200 QFF D13505F00A200 QFF D13506F00A200 QFF D13513F01A100 QFF D13513F00A100 QFF D13517F00A100 QFF D13700F01A100 TQF D13700F02A100 TQF	P13-64Pins		
D13503F01A200 QFF D13504F00A200 QFF D13505F00A200 QFF D13506F00A200 QFF D13513F01A100 QFF D13513F00A100 QFF D13517F00A100 QFF D13700F01A100 TQF D13700F02A100 TQF			
D13504F00A200 QFP D13505F00A200 QFP D13506F00A200 QFP D13513F01A100 QFP D13513F00A100 QFP D13517F00A100 QFP D13700F01A100 TQP D13700F02A100 TQP D13704F00A200 QFP	P12-48Pins		
D13505F00A200 QFP D13506F00A200 QFP D13513F01A100 QFP D13513F00A100 QFP D13517F00A100 QFP D13700F01A100 TQP D13700F02A100 TQP D13704F00A200 QFP	215-100Pins		
D13506F00A200 QFF D13513F01A100 QFF D13515F00A100 QFF D13517F00A100 QFF D13700F01A100 TQF D13700F02A100 TQF D13704F00A200 QFF	215-128Pins		
D13513F01A100 QFF D13515F00A100 QFF D13517F00A100 QFF D13700F01A100 TQF D13700F02A100 TQF D13704F00A200 QFF	215-128Pins		
D13515F00A100 QFF D13517F00A100 QFF D13700F01A100 TQF D13700F02A100 TQF D13700F02A100 QFF	215-128Pins		
D13517F00A100 QFP D13700F01A100 TQF D13700F02A100 TQF D13704F00A200 QFP	22-208Pins		
D13700F01A100 TQF D13700F02A100 TQF D13704F00A200 QFF	22-256Pins		
D13700F02A100 TQF D13704F00A200 QFF	215-128Pins		
D13704F00A200 QFF	P13-64Pins		
C	P13-64Pins		
	P14-80Pins		
UI3703F00AZ00 QFP	P14-80Pins		
D13706F00A200 TQF	TQFP15-100Pins		
D13719F00A100 QFF	QFP8-208Pins		
D13742F01A200 QFF	20-144Pins		
D13743F00A200 QFF	QFP20-144Pins		
D13746F01A600 QFF	215-128Pins		
D13748F00A100 QFF	20-144Pins		
D13781F00A100 QFF	215-100Pins		
D13A04F00A100 TQF	P15-128Pins		
D13A05F00A100 QFF	25-128Pins		
D13U11F00A100 QFF	20-144Pins		
R72013F00A100 QFF	QFP13-64Pins		
R72U06F12E100 QFF	P12-48Pins		
V30120F01A100 TQF	TQFP13-64Pins		
V3G340F00A900 QFF	QFP13-52Pins		
D13515F00A100 QFF	22-256Pins		
D13782F00A100 QFF	215-100Pins		
S65P10F00A000 QFF	15-100PINS		



Engineering Change Notice of Pure-Sn plating for QFP

Package: QFP

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1-1-E Page.1



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Please refer to following pages for detail of the change and evaluation result.



Details of engineering change as follows,

Items	Current	New		
Plating material	Sn-(1-3%)Bi	Pure-Sn		

Reliability results is as follows,

Test Items	Test condition	n	Terms of Test	Failure count	Judg ment
Solder ability1	Steam aging 4H→Solder dipping 245°C, 5sec	22	1 Time	0	Pass
Solder ability2	150°C,16H →Solder dipping 245°C, 5sec	22	1 Time	0	Pass
Solder ability3	Solder ability3 -40°C~125°C each 30 minute (After board assembly)		1,000 cyc.	0	Pass
Whisker test 1	Normal temp storage: 30°C60%RH	22	4,000 H	0	Pass
Whisker test 2High temp high humidity storage: 60°C90%RH		22	2,000 H	0	Pass
Whisker test 3	hisker test 3 Temp cycle: -40°C~85°C		1,000 cyc.	0	Pass

No defective confirmation in evaluation.

Solder ability test results

Pure-Sn plating



Solder ability1

Steam aging	:	4hrs
Flux dipping time	:	5~10sec
Solder temp.	:	245°C
Solder dipping time	:	5sec

Criteria

Solder wet rate more than 95%

Result

Pass. All terminal solder wets rate more than 95%

Solder ability2

High temp. storage	:	150°C16hrs
Flux dipping time	:	5~10sec
Solder temp.	:	245°C
Solder dipping time	:	5sec

	Solder ability1 Steam aging	Solder ability2 High temp storage			
Photo after solder dipping					

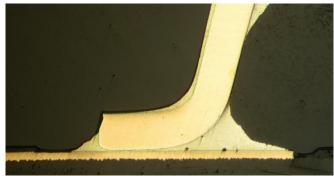
Board assembling test result Pure-Sn plating

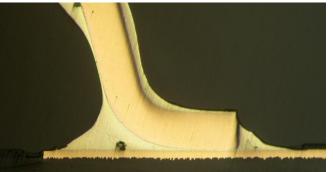


Sample	: P-LQFP048-0707-0.50(QFP12-48Pin) N=10
Board spec.	
-Dimension	$: 100 \text{mm} \times 100 \text{mm}$ t = 1.6 mm
-Material	: FR-4
-Layer count	: 1 layer (One side board)
-Cu layer	: 35µm
-Surface processing	: Water-soluble pre-flux processing
Solder paste	: Sn-3.0Ag-0.5Cu
Test condition	: $-40^{\circ}C \Leftrightarrow 125^{\circ}C$ (each 30 minute)
Judgment criteria	: A conduction part being left in the section part by section observation

Test result

: Pass. Because a conduction part is left in the section part after 1000cycle





<Representative photo after 1000 cycle >

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Whisker test result Pure-Sn plating



Sample : Pure-Sn plating						
2. High tem			 Normal tem High temp h Temperature 	high humidity : 60°C90%RH, 2000 hours		
Judgment criteria : Whisker length				n under 50µm		
Test result: 1. Normal temp. storage: Pass No whisker growth2. High temp high humidity: Pass No whisker growth3. Temperature cycle: Pass Under criteria						lo whisker growth
	Normal temp. 4000hrs			HT/HH 20	00hrs	Temp. cycle 1000cyc
	SEM photo		PSON LE 104 X1.00 10/m W0.8/mm		Max20µm EPSON LE 104 25.00 10 µm W0 8.7mm	

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Conclusion



- EPSON will change Terminal plating of QFP products, in order to unify specifications of "Pure-Sn" plating.
- •Heat-resistance and Reliability level are same as current products.
- •No difference of Terminal-strength and Soldering conditions.
- There is no difference in storage condition and handling conditions at customer side that is same as current products.